IN THE UNITED STATES PATENT AND TRADEMARK OFFICE PATENT APPLICATION EXAMINING OPERATIONS

Applicant: Ron A. Peters et al. Group Art Unit:

Serial No.: Examiner:

(Continuation of 10/013,185,

filed 12/07/2001)

Filed : Herewith Aty Dkt No.:

JEV/KAR:1016.2018

Title : PROBE STATION HAVING MULTIPLE ENCLOSURES

INFORMATION DISCLOSURE STATEMENT IN ACCORDANCE WITH 37 CFR §1.98

1600 ODS Tower 601 S.W. Second Avenue Portland, Oregon 97204-3157 July 8, 2003

Mail Stop PATENT APPLICATION Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Applicants submit herewith two(2) sheets of Form PTO-1449 (Modified) listing the patents and publications of which they are aware and which they desire to have considered by the Patent Office in accordance with 37 CFR §1.97. In accordance with 37 CFR §1.97(b)(1), this Information Disclosure Statement is being submitted together with the filing of the above-identified application.

In accordance with 37 CFR §1.97(h), the filing of this Information Disclosure Statement will not be regarded as an admission that any patent or publication or combination of patents referred to herein is, or is considered to be, material to patentability under 37 CFR §1.56(b) unless specifically designated as such.

A list of the patents and publications enclosed herewith is set forth on the attached 2 pages of Form PTO-1449 (Modified).

Copies of references AA-BX are not enclosed with this Information Disclosure Statement except for reference BA, for which a copy is enclosed. References AA-AZ and BB-BX were previously cited and submitted in prior U.S. patent application No. 08/870,335, filed June 6, 1997. Should the Examiner be unable to locate any of the references, he is invited to contact the undersigned attorney and copies of the references will be provided.

The person making this statement is the attorney who signs below on the basis of the information supplied by the inventor and the information in his file.

Respectfully submitted,

Jacob E. Vilhauer, Jr. Attorney for Applicants

Tel: (503) 227-5631

FORM PTO-1449 (Modified)

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO. JEV/KAR:1016.2018

SERIAL NO.

APPLICANT Ron A. Peters et al.

FILING DATE July 8, 2003 **GROUP**

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

			U.S. PA1	ENT DOCUMENTS		,	
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3,185,927	5/25/1965	Margulis et al.			
	AB	3,333,274	7/25/1967	Forcier			
	AC	3,405,361	10/8/1968	Kattner et al.			
	AD	3,710,251	1/9/1973	Hagge et al.			
	AE	4,115,736	9/19/1978	Tracy			
	AF	4,383,178	5/10/1983	Shibata et al.			
	AG	4,694,245	9/15/1987	Frommes			
	AH	4,731,577	3/15/1988	Logan			
	AI	4,755,746	7/5/1988	Mallory et al.			
	AJ	4,757,255	7/12/1988	Margozzi			
	AK	4,758,785	7/19/1988	Rath			
	AL	4,771,234	9/13/1988	Cook et al.			
	AM	4,845,426	7/4/1989	Nolan et al.			
	AN	4,856,904	8/15/1989	Akagawa			
,	AO	4,884,026	11/28/1989	Hayakawa et al.			
	AP	5,077,523	12/31/1991	Blanz			
	AQ	5,084,671	1/28/1992	Miyata et al.			
	AR	5,220,277	6/15/1993	Reitinger			
	AS	5,266,889	11/30/1993	Harwood et al.			
	AT	5,345,170	9/6/1994	Schwindt et al.			-
	AU	5,457,398	10/10/1995	Schwindt et al.	 		
	AV	5,963,027	10/5/1999	Peters			
	AW	6,002,263	12/14/1999	Peters et al.			
	AX	6,252,392	06/26/2001	Peters	 		
	AY	6,288,557	09/11/2001	Peters et al.	 		
	AZ	6,362,636	03/26/2002	Peters et al.	 -		
	BA	6,489,789	12/03/2002	Peters et al.	1		
-			FOREIGN P	ATENT DOCUMENTS		I	
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
					 		YES NO
	BB	1-209380	8/1989	Japan			
	BC	2-220453	9/1990	Japan			
	BD	201205	12/1986	European Patent Office	 		
	BE	3114466	3/1982	Germany			
	BF	2-022837	1/1990	Japan	- 		
	BG	4-000732	1/1992	Japan	1	I	

FORM PTO-1449 (Modified)	ATTY. DOCKET NO. JEV/KAR:1016.2018	SERIAL NO.		
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT Ron A. Peters et al.			
(Use several sheets if necessary)	FILING DATE July 8, 2003	GROUP		

	BH	"Model TPO3000 Series Thermochuck® Systems," four-page product note, Temptronic Corporation, Newton, MA				
		(May 1992 or earlier)				
	ві	"Application Note 1 Controlled Environment Enclosure," two-page application note, "Temptronic Corporation, Newton,				
		MA (May 1992 or earlier)				
ВЈ		"Cross Section Signatone S-1240," one-page sketch prepared by Signatone counsel, Signatone, San Jose, CA (February				
		1988 or earlier per Signatone)				
	вк	"S-1240," two-page product note, Signatone, San Jose, CA (February 1988 or ear	rlier per Signatone counsel)			
	BL Y. Yamamoto, "A Compact Self-Shielding Prober," IEEE Trans., Inst. and Meas., Vol. 38, pp 1088-1093					
	ВМ	Temptronic's "Guarded" Chuck, one-page note describing guarding system of Temptronic Corporation o				
		dated 11/15/89				
BN Beck & Tomann, "Chip Tester," IBM Technical Disclosure Bulletin, p. 4819 (January 1985)						
	во	Article by William Knauer entitled "Fixturing for Low-Current/Low Voltage Parametric Testing," appearing in				
		Evaluation Engineering, (1990) pp. 150-153				
	ВР	Hewlett-Packard, "Application Note 356-HP 4142B Modular DC Source/Monitor Practical Applications,"				
		(Nov. 1987) pp. 1-4				
	BQ	Hewlett-Packard, H-P Model 4284A Precision LCR Meter, Operation Manual (December 1991) pp. 2-1, 6-9 and 6-15				
	BR	Cascade Microtech, "Advanced On-Wafer Device Characterization Using the Summit 10500, (December 1992)				
	BS Micromanipulator Company, Inc., "Test Station Accessories," 1983. (month unavailable) BT Micromanipulator Company, Inc., "Model 8000 Test Station," 1986. (month unavailable)					
	BU	Micromanipulator Company, Inc., "Model 8000 Test Station," 1988. (month unavailable)				
	BV					
	BW					
	вх	Applebay, Harry F., Deposition transcript (pp. 61-67) with Exhibits 581 A, B, C describing Flexion AP-1 probe station				
i						

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.